

# RELIABILITY REPORT



**RELIABILITY DATA**  
**LT1395/96/97/98/99 LT6559**

**1/31/2008**

**• OPERATING LIFE TEST**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS <sup>(1)</sup> AT +125°C	NUMBER OF <sup>(2)</sup> FAILURES
SIDBRAZE	56	0213	0213	56.00	0
SOIC/SOT/MSOP	302	9901	9940	623.00	0
	358			679.00	0

**• PRESSURE COOKER TEST AT 15 PSIG, +121°C**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS	NUMBER OF FAILURES
SOIC/SOT/MSOP	1,797	9838	0705	382.54	0
SSOP/TSSOP	345	9838	0333	20.83	0
QFN/DFN	50	0235	0235	16.80	0
	2,192			420.17	0

**• TEMP CYCLE FROM -65°C to +150°C**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SOIC/SOT/MSOP	1,876	9838	0705	617.64	0
SSOP/TSSOP	350	9838	0333	35.00	0
QFN/DFN	50	0235	0235	50.10	0
	2,276			702.74	0

**• THERMAL SHOCK FROM -65°C to +150°C**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SOIC/SOT/MSOP	1,563	9838	0705	584.95	0
SSOP/TSSOP	350	9838	0333	35.00	0
	1,913			619.95	0

(1) Assumes Activation Energy = 1.0 Electron Volts

(2) Failure Rate Equivalent to +55°C, 60% Confidence Level = 2.71 FITS

(3) Mean Time Between Failures in Years = 42,095

Note: 1 FIT = 1 Failure in One Billion Hours.